

# GL9960

**N-CHANNEL ENHANCEMENT MODE POWER MOSFET**

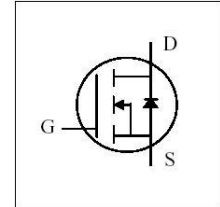
BV <sub>DSS</sub>	40V
R <sub>DS(ON)</sub>	20mΩ
I <sub>D</sub>	7.8A

## Description

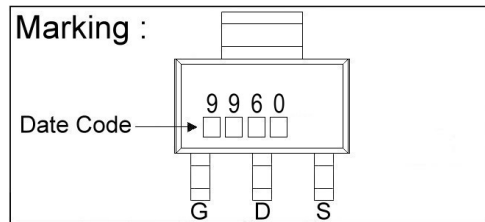
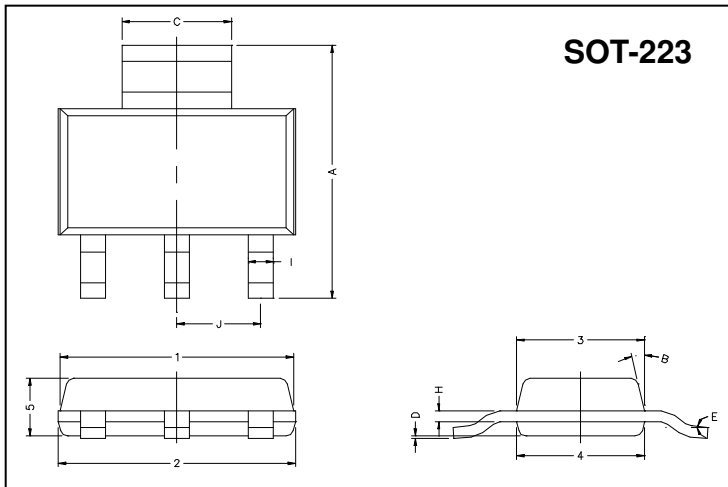
The GL9960 provide the designer with the best combination of fast switching, ruggedized device design, ultra low on-resistance and cost-effectiveness.

## Features

- \*Low On-Resistance
- \*Fast Switching Speed



## Package Dimensions



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.70	7.30	B	13°TYP.	
C	2.90	3.10	J	2.30 REF.	
D	0.02	0.10	1	6.30	6.70
E	0°	10°	2	6.30	6.70
I	0.60	0.80	3	3.30	3.70
H	0.25	0.35	4	3.30	3.70
			5	1.40	1.80

## Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	40	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current <sup>3</sup>	I <sub>D</sub> @TA=25°C	7.8	A
Continuous Drain Current <sup>3</sup>	I <sub>D</sub> @TA=70°C	6.2	A
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	20	A
Total Power Dissipation	P <sub>D</sub> @TA=25°C	2.7	W
Linear Derating Factor		0.02	W/°C
Operating Junction and Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 ~ +150	°C

## Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-ambient <sup>3</sup> Max.	R <sub>thj-amb</sub>	45	°C/W

**Electrical Characteristics (T<sub>j</sub> = 25°C unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> =250uA
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_j$	-	0.032	-	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	-	3.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Forward Transconductance	g <sub>fs</sub>	-	25	-	S	V <sub>DS</sub> =10V, I <sub>D</sub> =7A
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	I <sub>DSS</sub>	-	-	1	uA	V <sub>DS</sub> =40V, V <sub>GS</sub> =0
Drain-Source Leakage Current(T <sub>j</sub> =70°C)		-	-	25	uA	V <sub>DS</sub> =32V, V <sub>GS</sub> =0
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	-	-	20	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =7A
		-	-	32		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	-	14.7	-	nC	I <sub>D</sub> =7A V <sub>DS</sub> =20V V <sub>GS</sub> =4.5V
Gate-Source Charge	Q <sub>gs</sub>	-	7.1	-		
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	-	6.8	-		
Turn-on Delay Time <sup>2</sup>	T <sub>d(on)</sub>	-	11.5	-	ns	V <sub>DS</sub> =20V I <sub>D</sub> =1A V <sub>GS</sub> =10V R <sub>G</sub> =3.3Ω R <sub>D</sub> =20Ω
Rise Time	T <sub>r</sub>	-	6.3	-		
Turn-off Delay Time	T <sub>d(off)</sub>	-	28.2	-		
Fall Time	T <sub>f</sub>	-	12.6	-		
Input Capacitance	C <sub>iss</sub>	-	1725	-	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =25V f=1.0MHz
Output Capacitance	C <sub>oss</sub>	-	235	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	145	-		

**Source-Drain Diode**

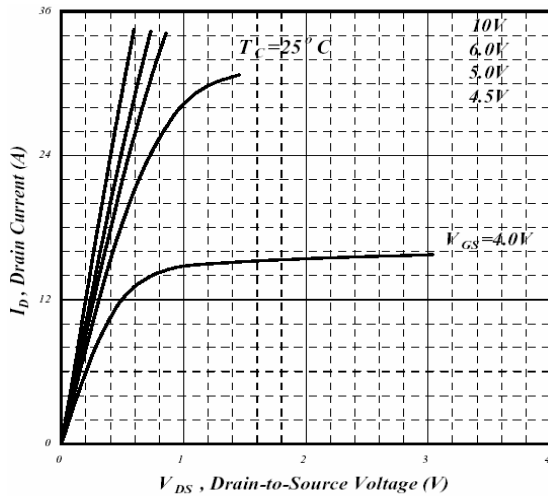
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage <sup>2</sup>	V <sub>SD</sub>	-	-	1.3	V	I <sub>S</sub> =2.3A, V <sub>GS</sub> =0V, T <sub>j</sub> =25°C
Continuous Source Current (Body Diode)	I <sub>S</sub>	-	-	2.3	A	V <sub>D</sub> = V <sub>G</sub> =0V, V <sub>S</sub> =1.3V
Pulsed Source Current (Body Diode) <sup>1</sup>	I <sub>SM</sub>	-	-	20	A	

Notes: 1. Pulse width limited by Max. junction temperature.

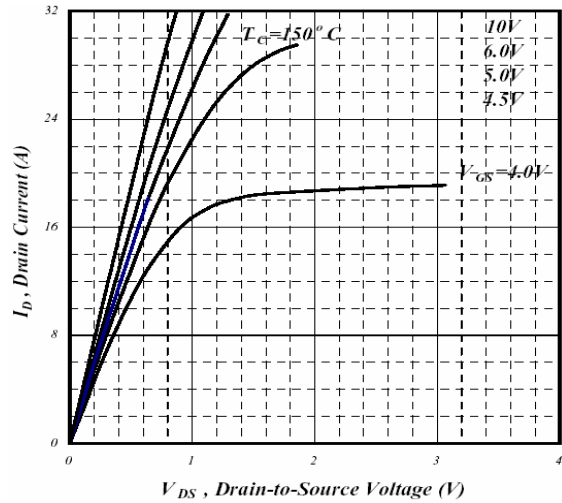
2. Pulse width ≤ 300us, duty cycle ≤ 2%.

3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board; 135°C/W when mounted on min. copper pad.

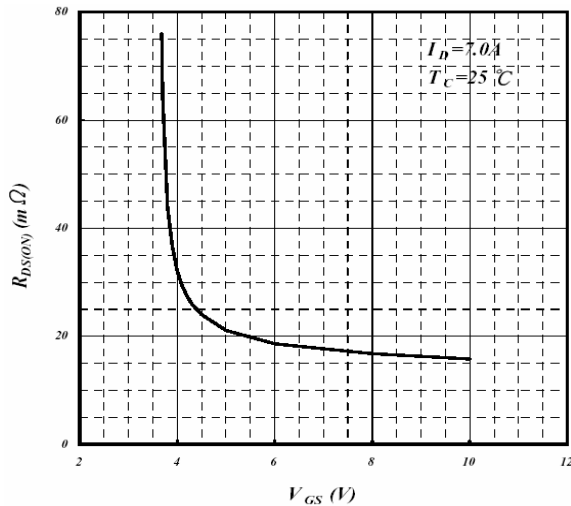
## Characteristics Curve



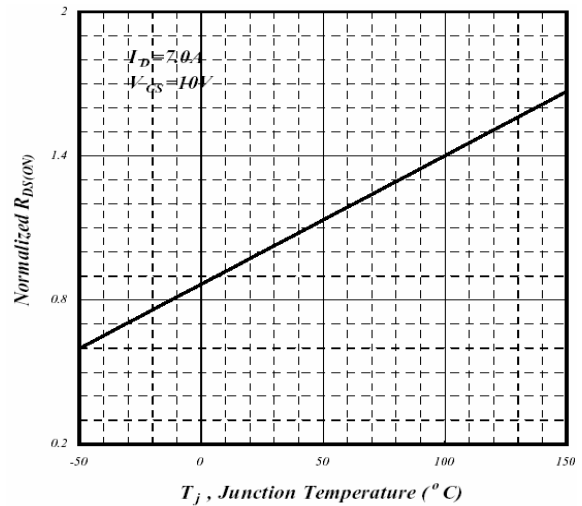
**Fig 1. Typical Output Characteristics**



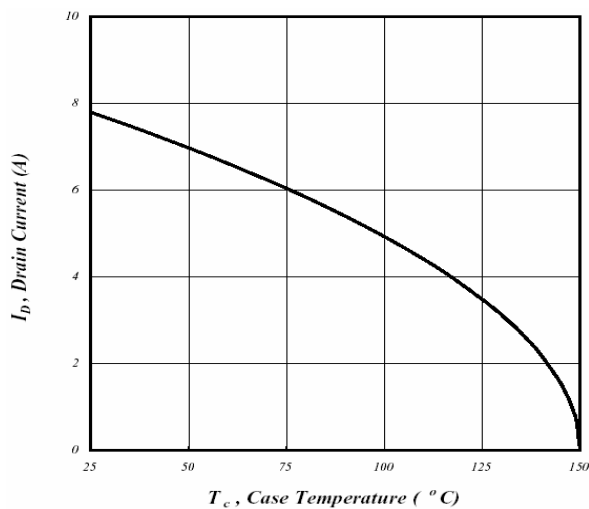
**Fig 2. Typical Output Characteristics**



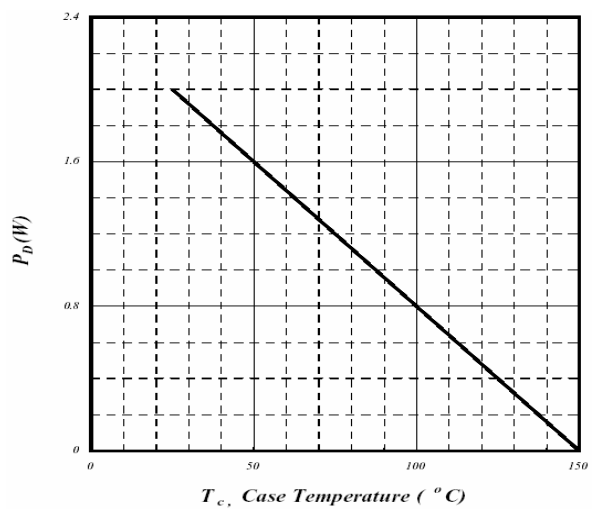
**Fig 3. On-Resistance v.s. Gate Voltage**



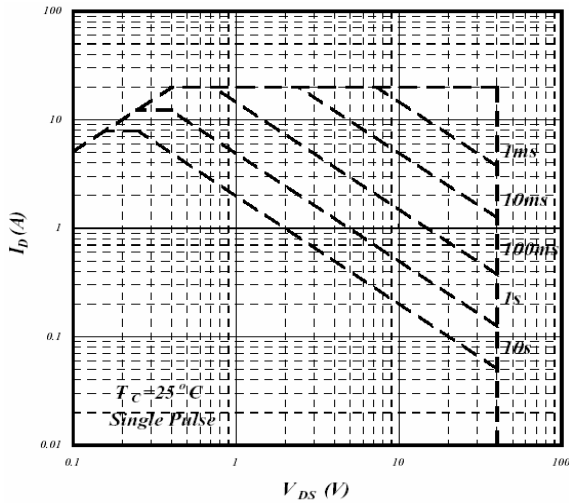
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



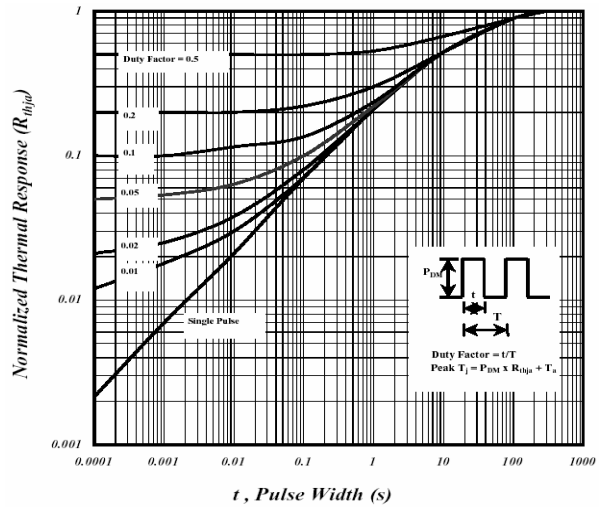
**Fig 5. Maximum Drain Current v.s. Case Temperature**



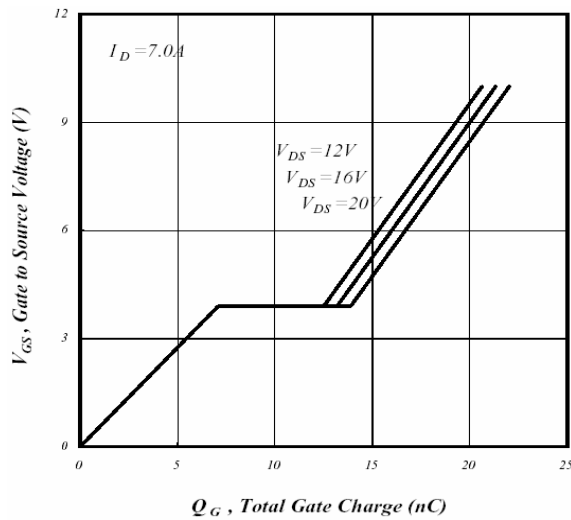
**Fig 6. Type Power Dissipation**



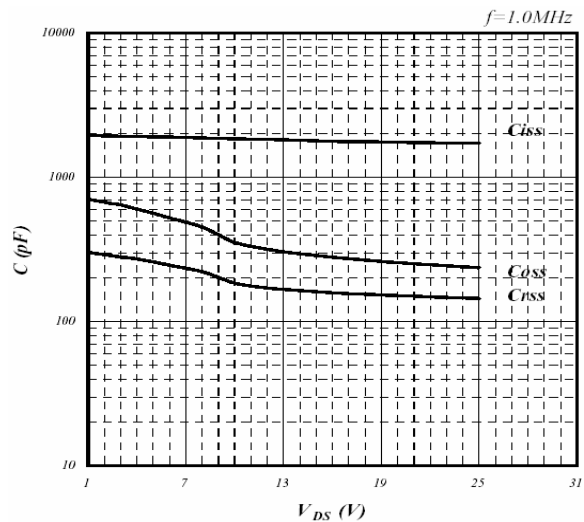
**Fig 7. Maximum Safe Operating Area**



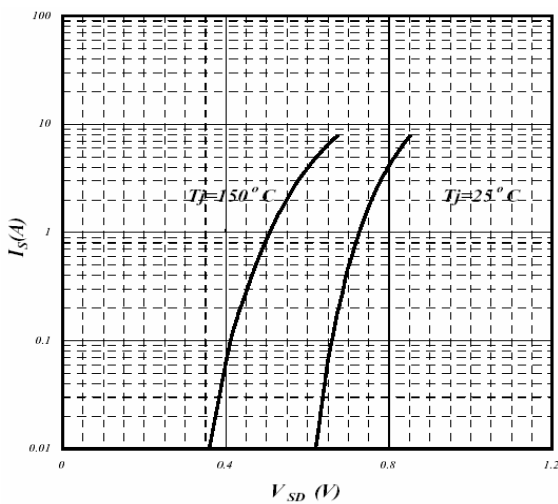
**Fig 8. Effective Transient Thermal Impedance**



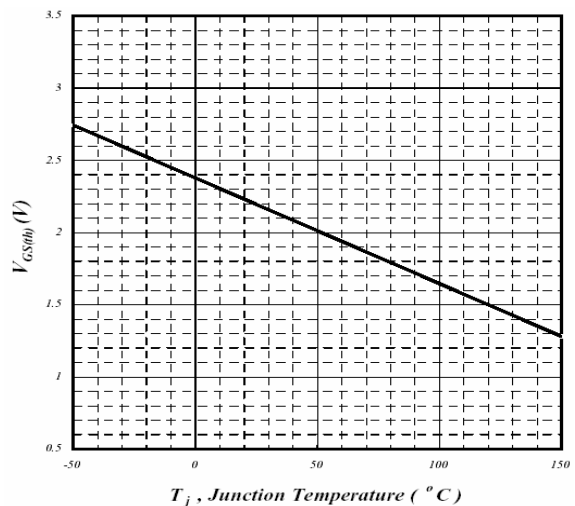
**Fig 9. Gate Charge Characteristics**



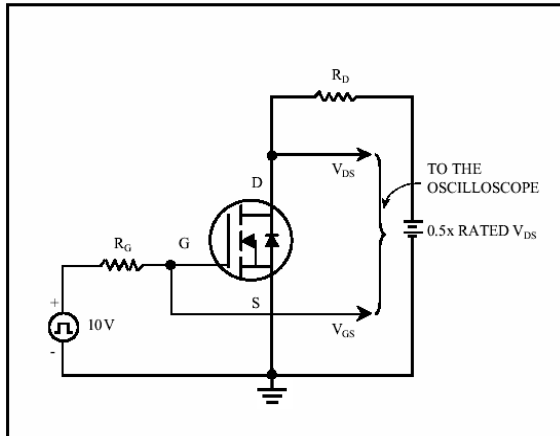
**Fig 10. Typical Capacitance Characteristics**



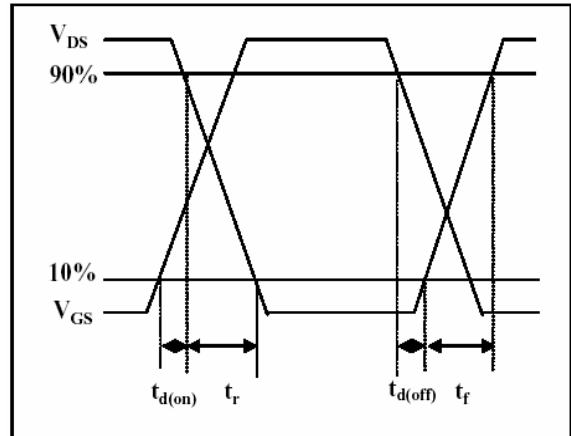
**Fig 11. Forward Characteristics of Reverse Diode**



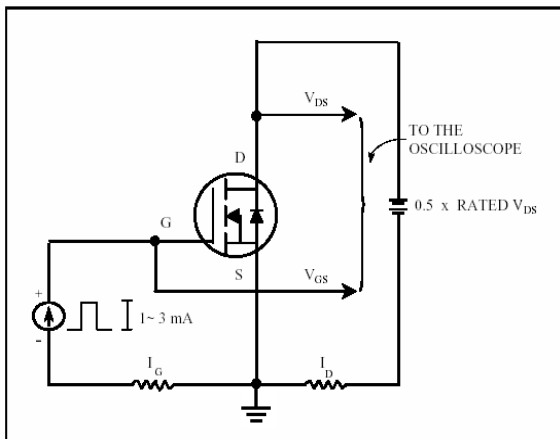
**Fig 12. Gate Threshold Voltage v.s. Junction Temperature**



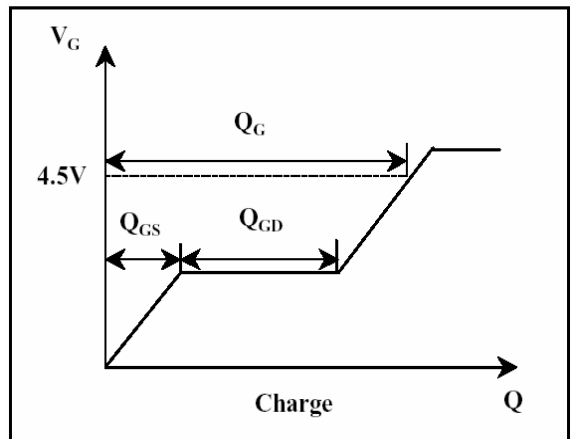
**Fig 13. Switching Time Circuit**



**Fig 14. Switching Time Waveform**



**Fig 15. Gate Charge Circuit**



**Fig 16. Gate Charge Waveform**

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